

Notice of References Cited

Application/Control No.

10/564,848

Applicant(s)/Patent Under
Reexamination
MIN ET AL.

Examiner

Richard G. Keehn

Art Unit

2152

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0046338 A1	03-2003	Runkis, Walter H.	709/203
*	B	US-2005/0262217 A1	11-2005	Nonaka et al.	709/217
*	C	US-2003/0206728 A1	11-2003	Ichikawa et al.	386/125
*	D	US-2003/0142956 A1	07-2003	TOMITA et al.	386/69
*	E	US-2002/0165987 A1	11-2002	Arisaka et al.	709/246
*	F	US-2004/0198217 A1	10-2004	Lee et al.	455/003.01
*	G	US-2004/0003073 A1	01-2004	Krzyzanowski et al.	709/223
*	H	US-2003/0133558 A1	07-2003	KUNG et al.	379/215.01
*	I	US-5,867,494	02-1999	Krishnaswamy et al.	370/352
*	J	US-7,085,814 B1	08-2006	Gandhi et al.	709/208
*	K	US-5,751,338	05-1998	Ludwig, Jr., Lester Frank	348/14.12
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.